

L Number	Hits	Search Text	DB	Time stamp
-	300	(gan or gallium adj nitride) and blue and trench	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/01 12:35
-	2	"6327288"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/31 17:03
-	1	"6153010".PN.	USPAT	2004/03/31 17:04
-	0	6327288.URPN.	USPAT	2004/03/31 17:04
-	235	lateral adj waveguide	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/01 12:36
-	43	trench and (lateral adj waveguide)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/01 12:52
-	311	(438/31).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/01 12:57
-	4	(gallium adj nitride or gan) and trench and ((438/31).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/01 13:01
-	12	(gallium adj nitride or gan) and trench and lateral adj waveguide	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/01 13:00
-	583	(438/46).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/01 13:01
-	21	(gallium adj nitride or gan) and trench and ((438/46).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/01 13:08
-	241	(438/481).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/01 13:12
-	160	(438/483).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/01 13:13

=> file inspec			
COST IN U.S. DOLLARS	SINCE FILE	TOTAL	
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FULL ESTIMATED COST	0.21	0.21	

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 FILE COVERS 1969 TO DATE.

<<< SIMULTANEOUS LEFT AND RIGHT TRUNCATION AVAILABLE IN  
 THE BASIC INDEX >>>

=> s lateral waveguide  
 47025 LATERAL  
 72225 WAVEGUIDE  
 L1 45 LATERAL WAVEGUIDE  
 (LATERAL (W) WAVEGUIDE)

=> s trench  
 L2 5853 TRENCH

=> s l1 and l2  
 L3 1 L1 AND L2

=> d l3

L3 ANSWER 1 OF 1 INSPEC (C) 2004 IEE on STN

  
 Full Text  
 AN 1999:6372055 INSPEC DN B1999-11-4140-015  
 TI Polymeric optical mode converter for hybrid photonic integrated circuits.  
 AU Bakke, T.; Mukherjee, S.D. (Dept. of Phys. Electron., Norwegian Univ. of Sci. & Technol., Trondheim, Norway)  
 SO Proceedings of the SPIE - The International Society for Optical Engineering (1999) vol.3632, p.234-41. 9 refs.  
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 TC Theoretical; Experimental  
 CY United States  
 LA English

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